

PROTOCOL 6/2018
Dielectric absorption tests at room temperature
in the frequency range from 10^{-1} Hz to 10^7 Hz
for the Composite Adhesive Matrix, ADR Technology

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1. Aim of the research: determination of the dielectric absorption window for various ADR Technology Adhesives / Matrixes in the frequency range of 10^{-1} Hz - 10^7 Hz at room temperature. The ADR Technology samples were provided by Stanisław Wosiński.

2. Method of measurement: the dielectric is characterized by a relative complex permittivity:

$$\varepsilon^* = \varepsilon' - j\varepsilon'', \quad (1)$$

where "relative" means normalization against the in vacuo dielectric constant $\varepsilon_0 = 8.85 \times 10^{-12}$ F/m.

$$\varepsilon'' = \varepsilon_p'' + \frac{\sigma_{dc}}{\varepsilon_0 f}, \quad (2)$$

are the sum of losses associated with dielectric polarization ε_p'' and ohmic loss $\sigma_{dc}/\varepsilon_0 f$ (σ_{dc} means DC conductivity, f is the frequency of the measuring field). Both electric permeability ε^* as well as the tangent of the dielectric loss angle

$$\tan \delta = \frac{\varepsilon''}{\varepsilon'} = \frac{\left(\varepsilon_p'' + \frac{\sigma_{dc}}{\varepsilon_0 f}\right)}{\varepsilon'} \quad (3)$$

they depend on the frequency of the measuring field. In the frequency range f from 1×10^{-1} Hz do 1×10^7 Hz, dielectric properties are measured in a system in which the sample fills the measuring capacitor (a flat condenser).

3. The apparatus and experiment of the dielectric response of the sample were tested using the Alpha-A High Performance Frequency Analyzer (Novocontrol GmbH). The sample was a Composite filled flat condenser with a diameter of 20 mm and a thickness of 0.13 – 0.36 mm, placed at room temperature (293 K). Impedance Z' (od $10^{-3} \Omega$ do $10^{15} \Omega$), Capacity C (10^{-15} F do 1 F) and the tangent of the dielectric loss angle $\tan \delta$ measured over a period of 8 decades of frequency (1×10^{-1} Hz do 1×10^7 Hz) at a sampling voltage of 1V. The real part of the electrical permittivity ε' samples were calculated from the dependence:

$$\varepsilon' = \frac{d}{\varepsilon_0 S} C, \quad (4)$$

where d - means the thickness of the sample (w m), S is the surface of the sample (w m²), C – its capacity (w F) and a $\varepsilon_0 = 8.85 \times 10^{-12}$ F/m) is the dielectric constant of the vacuum. The imaginary part ε'' of the complex permittivity of the sample is:

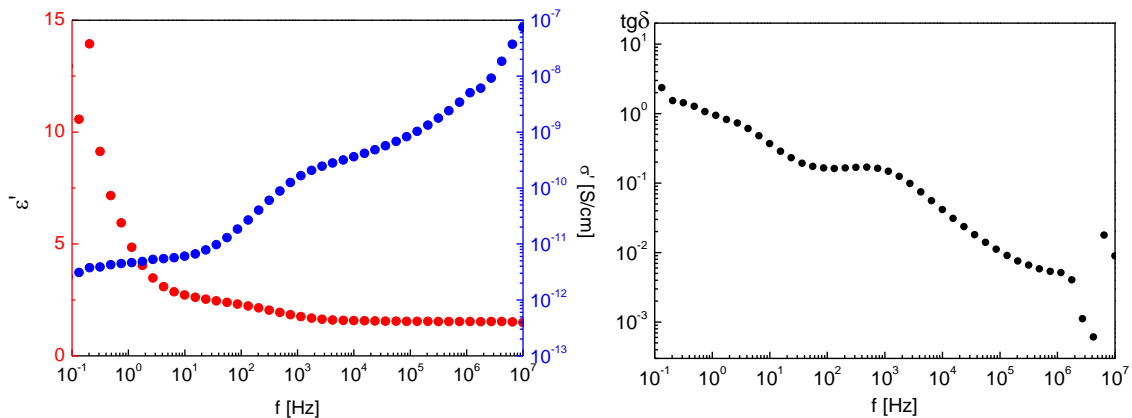
$$\varepsilon'' = \varepsilon' \tan \delta. \quad (5)$$

The measured values were stored in memory and the sample characterizing quantities were calculated using WinDETA impedance analysis software and the WinFit V 3.2. Program.

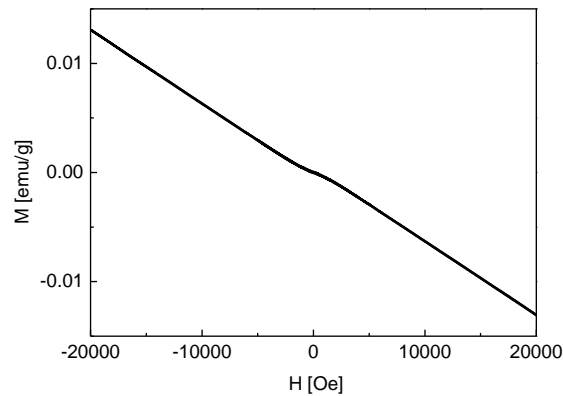
4. Results. Four series of dielectric measurements (3 measurements) were carried out for each ADR Technology sample.

Series I - Composite Glue / Matrix 1

The measurements were made in an open space with a relative humidity of ~ 20% at room temperature (293 K) for the sample provided by ADR Technology. The results presented are the average of 3 measurements. In addition to ADR technology, the sample was: Saltadis adhesive and Lenko S.A. foil.

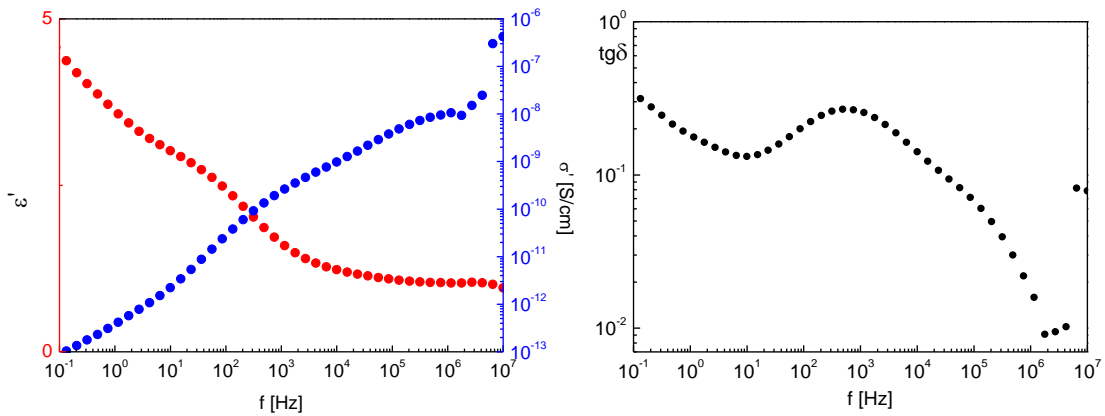


For **Series I**, a magnetic hysteresis loop measurement was also carried out at room temperature. The material tested has diamagnetic properties.



Series II - Composite Glue / Matrix 2

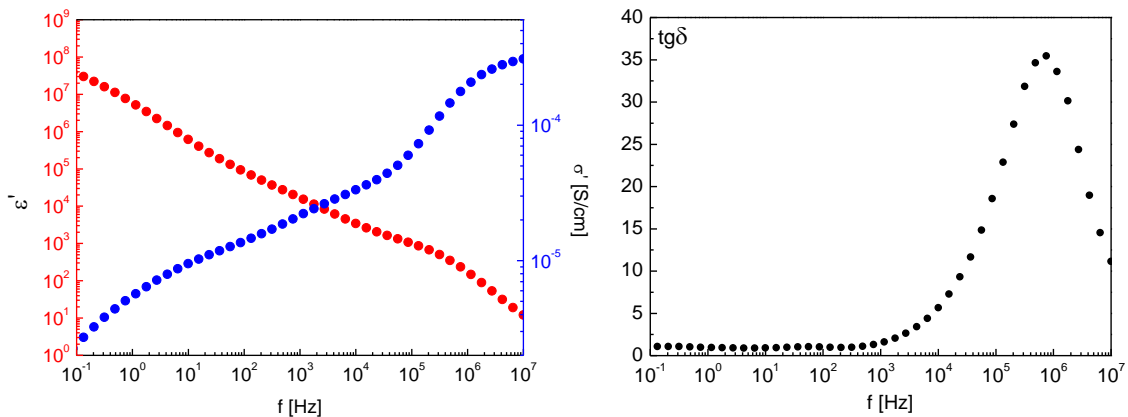
The measurements were made in an open space with a relative humidity of $\sim 20\%$ at room temperature (293 K) for the sample provided by ADR Technology. The results presented are the average of 3 measurements. In addition to ADR technology, there was a sample of Saltadis adhesive.



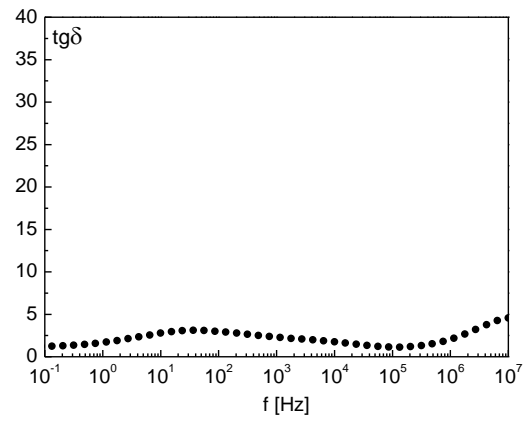
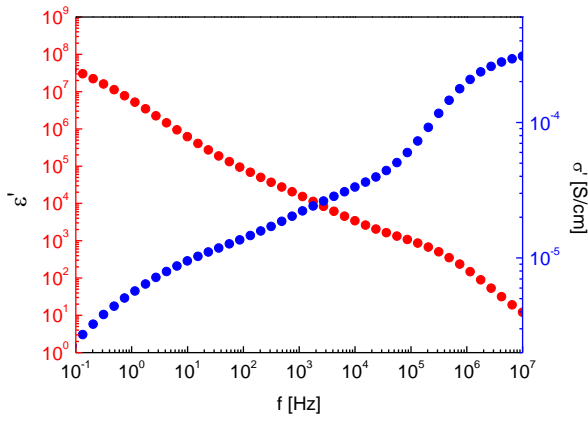
Series III / IV Composite Glue / Matrix 3

The measurements were made in an open space with a relative humidity of $\sim 20\%$ at room temperature (293 K) for the sample provided by ADR Technology. In addition to ADR technology, there was a sample of Saltadis adhesive. Series III and IV were made within 30 minutes. The first measurement of each series differs from the others in both cases.

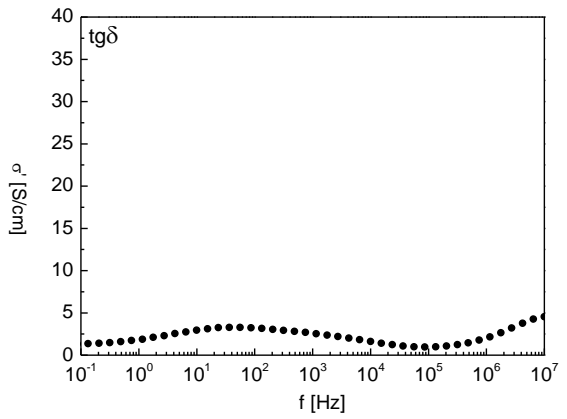
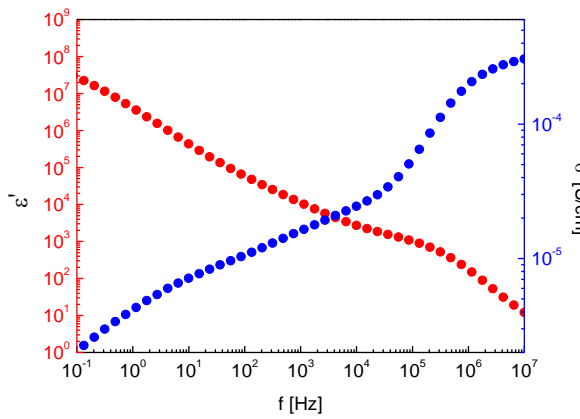
Series III - measurement 1



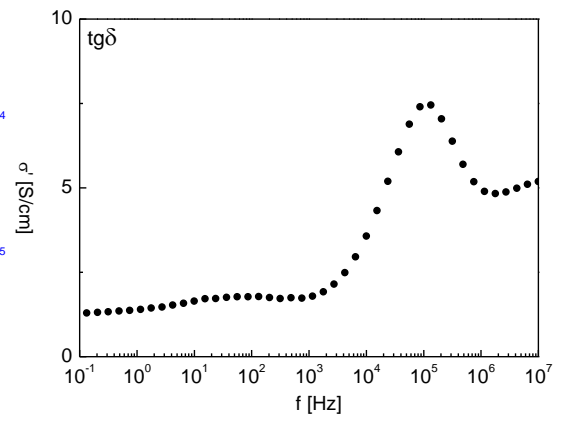
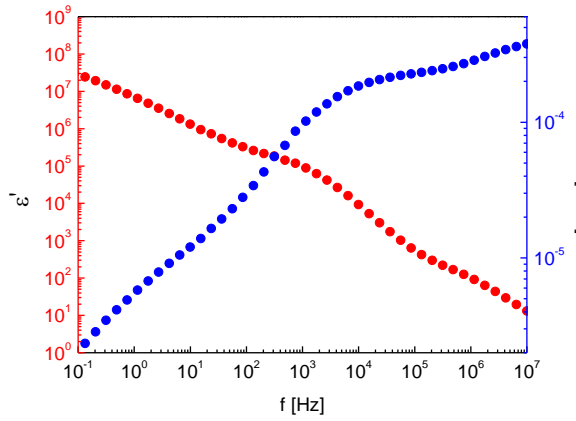
Series III - Measurement 2



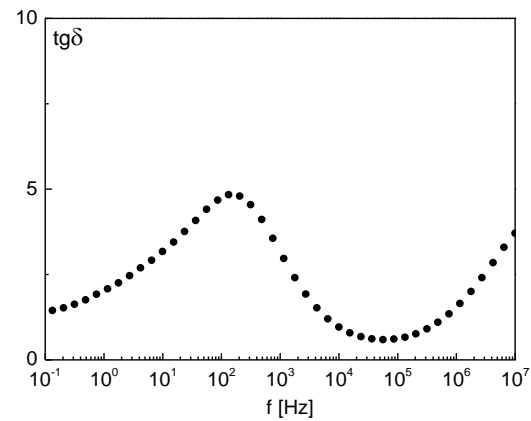
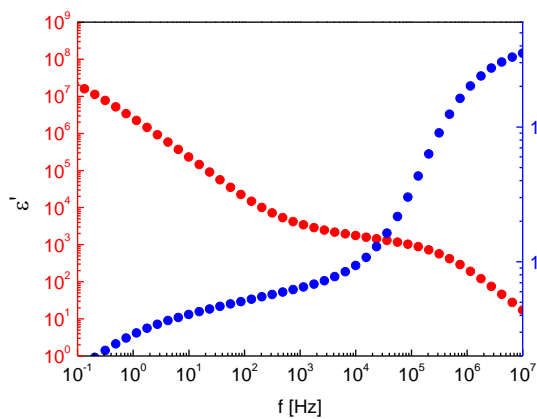
Seria III – Measurement 3



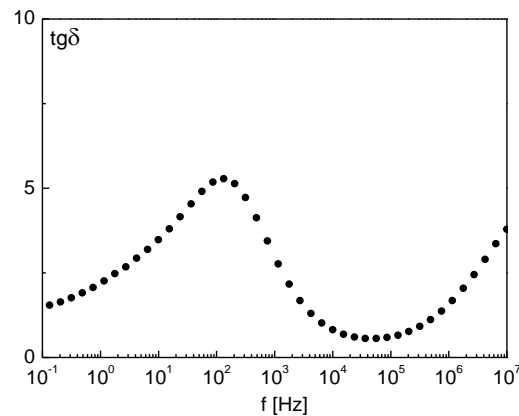
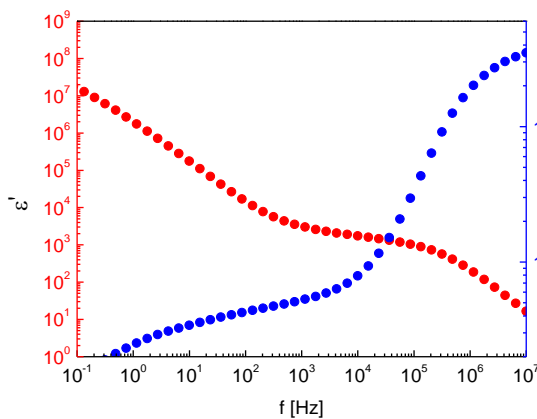
Series IV – measurement 1



Series IV – measurement 2



Series IV –measurement 3



5. Summary

- i) The Saltadis adhesive with ADR technology placed between metal electrodes (Series III and IV) has dielectric properties suitable for EMF shielding in the whole frequency range of 0.1 Hz – 10 MHz. Measurements, however, indicate that it was measured in a non-stabilized state (non-aging).
- ii) Saltadis adhesive composites with ADR technology and foil from Lenko exhibit very low ϵ' values and low dielectric losses. Due to the dielectric properties of the adhesive, we suggest re-measuring this system with other electrodes.
- iii) Saltadis adhesive composites with ADR technology and foil from Lenko have diamagnetic properties.
- iv) We believe that both the adhesive and the entire system require research on the stabilization process (aging).